



## CLUSTER DETECTOR TEST REPORT

**CLUSTER DETECTOR No. 16**  
**Test carried on 09.12.11 – 10.12.11**

Ch.	HEX	U <sub>op</sub> [V]	U <sub>op</sub> – 500 V		U <sub>op</sub>			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{FWHM}$	Pos. [Ch.]	FWHM [keV]
A	156	4000	2.11	n.c.	1.99	n.c.	6258	
B	169	3000	2.04	n.c.	1.95	n.c.	6386	
C	45	4500	2.18	n.c.	2.17	n.c.	6904	
D	92	4000	2.08	n.c.	1.88	n.c.	8835	
E	163	3000	1.93	n.c.	1.86	n.c.	4780	
F	149	4000	1.96	n.c.	1.88	n.c.	6303	
G	152	3000	2.03	n.c.	1.95	n.c.	6448	

**Operational Temperature: -154.9 °C**

**Date:**

**Tested by:**  
**/I.Kojouharov/**

### **Assembly and test remarks:**

Regular test after assembly at RIKEN

Recommended ch.C 4000 V operational voltage instead 4500.

### **Test Equipment:**

HV – ORTEC 660

Main Amplifier – ORTEC 671,  $\tau = 6 \mu\text{s}$ , Gain 100 x 0.72

ADC – 4801A (RIKEN), MCA -PC98B

Source -  $^{60}\text{Co}$